

• General Description

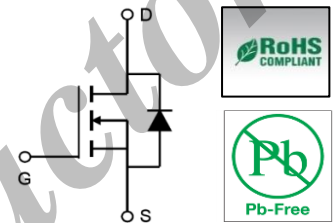
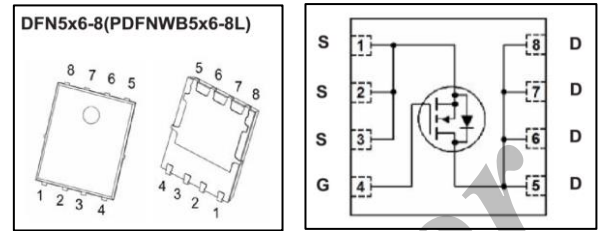
APN6512 combines advanced MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$. This device is most suitable to load-switch or DC/DC conversion applications.

• Applications

- DC/DC Converters in Computing, Servers, and POL
- Isolated DC/DC Converters in Telecom and Industrial

• Product Summary

V_{DS}	30V
$I_{D(MAX)}$ (at $V_{GS} = 10V$)	150A
$R_{DS(ON)}$ (at $V_{GS} = 10V$)	< 1.7 m Ω
$R_{DS(ON)}$ (at $V_{GS} = 4.5V$)	< 2.4 m Ω



• Absolute Maximum Ratings $T_a = 25^\circ C$

Parameter	Symbol	Rating	Unit	
Drain-Source Voltage	V_{DS}	30	V	
Gate-Source Voltage	V_{GS}	± 20		
Continuous Drain Current ^G	I_D	$T_c=25^\circ C$	150	A
		$T_c=100^\circ C$	115	
Pulsed Drain Current ^C	I_{DM}	340		
Continuous Drain Current	I_{DSM}	$T_A=25^\circ C$	54	
		$T_A=25^\circ C$	43	
Avalanche Current ^C	I_{AS}	70		
Avalanche Energy $L = 0.05 \text{ mH}$ ^C	E_{AS}	123	mJ	
V_{DS} Spike	V_{SPIKE}	36	V	
Power Dissipation ^B	P_D	$T_c=25^\circ C$	83	W
		$T_c=100^\circ C$	33	
Power Dissipation ^A	P_{DSM}	$T_A=25^\circ C$	7.4	
		$T_A=70^\circ C$	4.7	
Thermal Resistance.Junction- to-Ambient ^A	R_{thJA}	$t \leq 10s$	17	$^\circ C/W$
Thermal Resistance.Junction- to-Ambient ^{A,D}		Steady-State	55	
Thermal Resistance.Junction- to-Case	R_{thJC}	Steady-State	1.5	
Junction Temperature	T_J	150	$^\circ C$	
Storage Temperature Range	T_{stg}	-55 to 150		

Notes:

- A. The value of R_{thJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ C$. The Power dissipation P_{DSM} is based on R_{thJA} and the maximum allowed junction temperature of 150 $^\circ C$. The value in any given application depends on the user's specific board design.
- B. The power dissipation P_D is based on $T_J(MAX)=150^\circ C$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
- C. Single pulse width limited by junction temperature $T_J(MAX)=150^\circ C$.
- D. The R_{thJA} is the sum of the thermal impedance from junction to case R_{thJC} and case to ambient.
- G. The maximum current rating is package limited.

• **Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)**

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$I_D = 250 \mu\text{A}$, $V_{GS} = 0\text{V}$	30			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 30\text{V}$, $V_{GS} = 0\text{V}$			1	μA
		$V_{DS} = 30\text{V}$, $V_{GS} = 0\text{V}$, $T_J = 55^\circ\text{C}$			5	
Gate to Source Leakage Current	I_{GSS}	$V_{DS} = 0\text{V}$, $V_{GS} = \pm 20\text{V}$			± 100	nA
Gate to Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250\mu\text{A}$	1		2	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 10\text{V}$, $I_D = 20\text{A}$			1.7	m Ω
		$V_{GS} = 10\text{V}$, $I_D = 20\text{A}$, $T_J = 125^\circ\text{C}$			2.3	
		$V_{GS} = 4.5\text{V}$, $I_D = 20\text{A}$			2.4	
Forward Transconductance	g_{FS}	$V_{DS} = 5\text{V}$, $I_D = 20\text{A}$		85		S
Input Capacitance	C_{iss}	$V_{GS} = 0\text{V}$, $V_{DS} = 15\text{V}$, $f = 1\text{MHz}$		3430		pF
Output Capacitance	C_{oss}			1327		
Reverse Transfer Capacitance	C_{rss}			175		
Gate Resistance	R_g	$V_{GS} = 0\text{V}$, $V_{DS} = 0\text{V}$, $f = 1\text{MHz}$	0.3		1.1	Ω
Total Gate Charge	$Q_g(10\text{V})$	$V_{GS} = 10\text{V}$, $V_{DS} = 15\text{V}$, $I_D = 20\text{A}$		53	64	nC
Total Gate Charge	$Q_g(4.5\text{V})$			25	30	
Gate Source Charge	Q_{gs}			7.8		
Gate Drain Charge	Q_{gd}			10.3		
Turn-On DelayTime	$t_{d(on)}$	$V_{GS} = 10\text{V}$, $V_{DS} = 15\text{V}$, $R_L = 0.75\Omega$, $R_{GEN} = 3\Omega$		7.5		ns
Turn-On Rise Time	t_r			5.0		
Turn-Off DelayTime	$t_{d(off)}$			33.8		
Turn-Off Fall Time	t_f			9.8		
Body Diode Reverse Recovery Time	t_{rr}			22		
Body Diode Reverse Recovery Charge	Q_{rr}	$I_F = 20\text{A}$, $di/dt = 500\text{A}/\mu\text{s}$		58		nC
Maximum Body-Diode Continuous Current	I_S				85	A
Diode Forward Voltage	V_{SD}	$V_{GS} = 0\text{V}$, $I_S = 1\text{A}$			1	V

Notes:

E. The static characteristics in Figures 1 to 6 are obtained using <300s pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)} = 150^\circ\text{C}$. The SOA curve provides a single pulse rating.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$.

• **Ordering Information**

Ordering Part Number	Package	MOQ
APN6512	DFN5x6-8 (PDFNWB5x6-8L)	5,000 pcs / reel

THIS PRODUCT HAS BEEN DESIGNED AND QUALIFIED FOR THE CONSUMER MARKET. APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. APOLLO SEMICONDUCTOR DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. APOLLO SEMICONDUCTOR RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE.

• Typical Characteristics

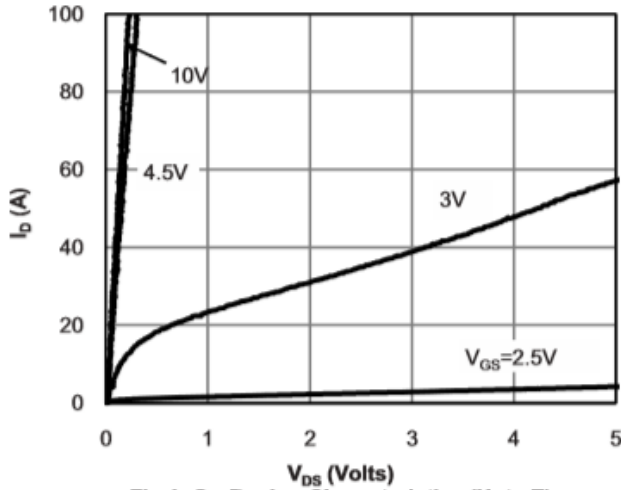


Fig 1: On-Region Characteristics (Note E)

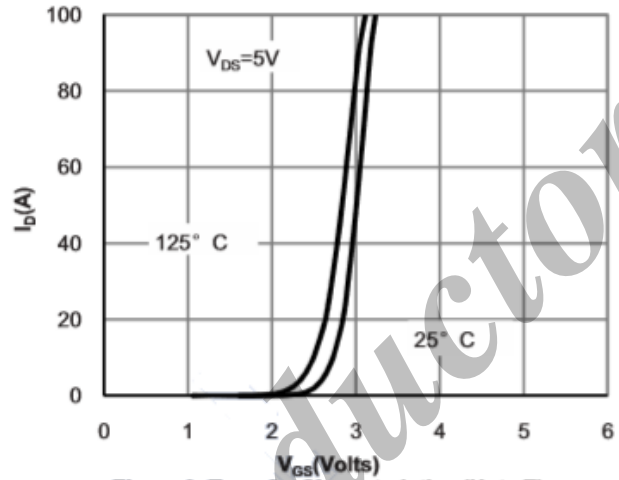


Figure 2: Transfer Characteristics (Note E)

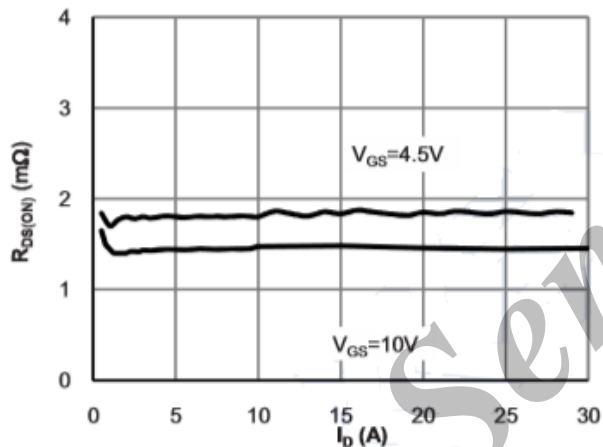


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

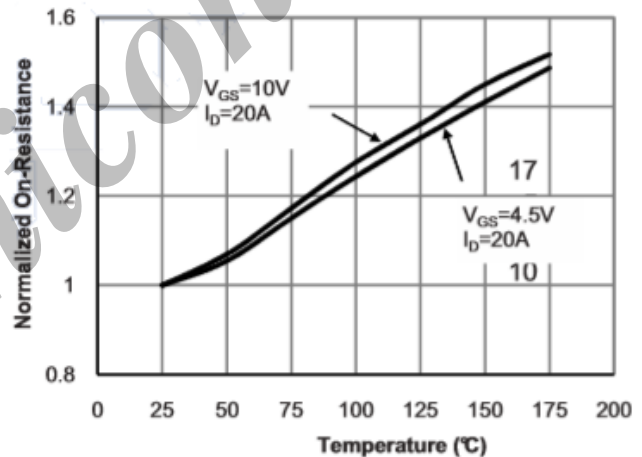


Figure 4: On-Resistance vs. Junction Temperature (Note E)

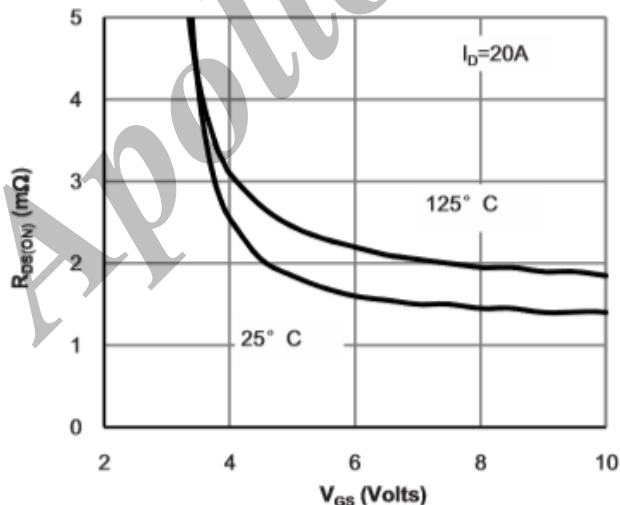


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

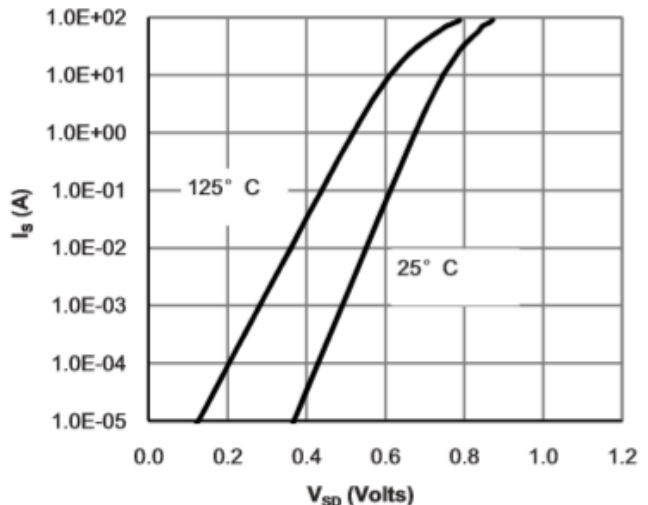


Figure 6: Body-Diode Characteristics (Note E)

• Typical Characteristics

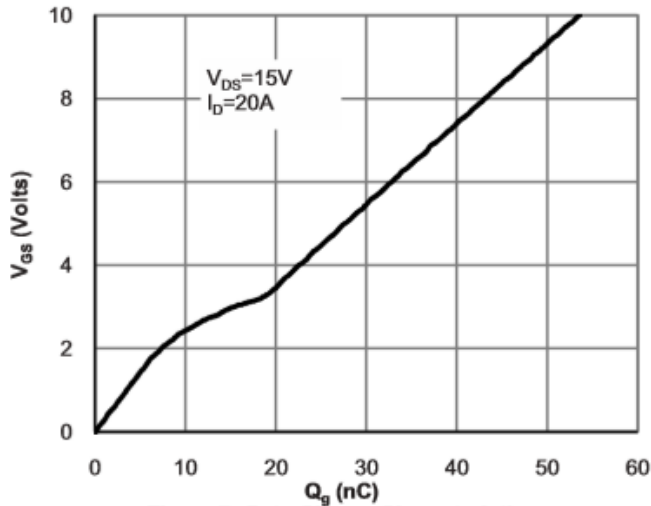


Figure 7: Gate-Charge Characteristics

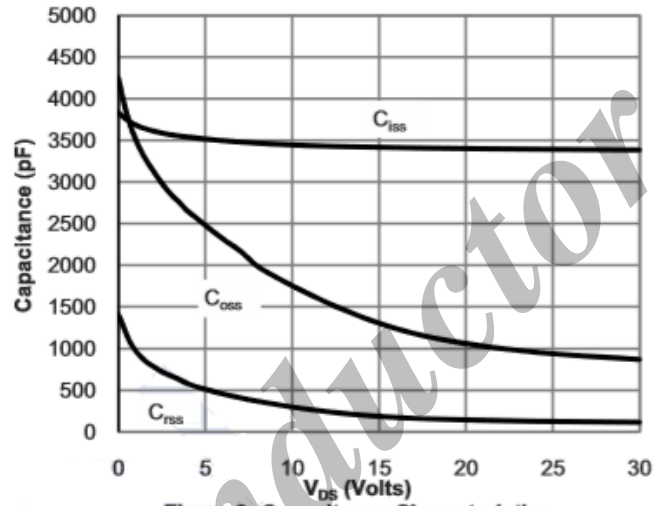


Figure 8: Capacitance Characteristics

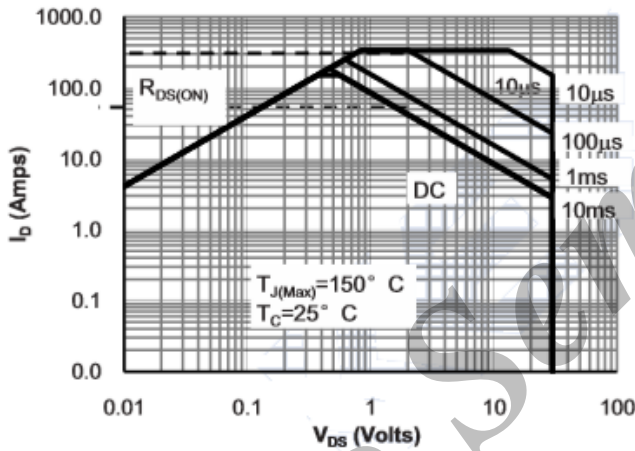


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

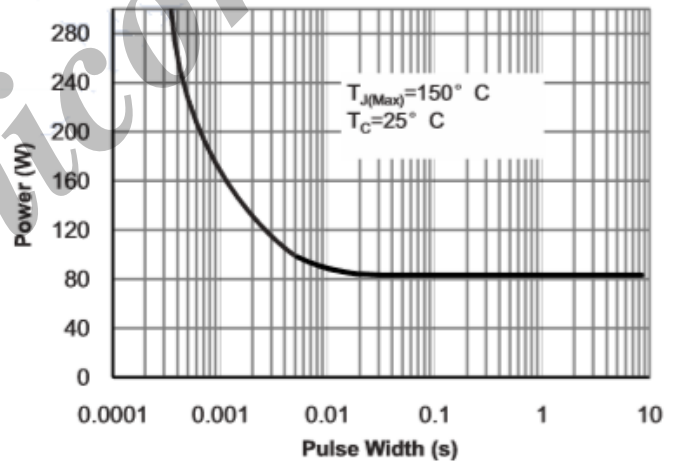


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

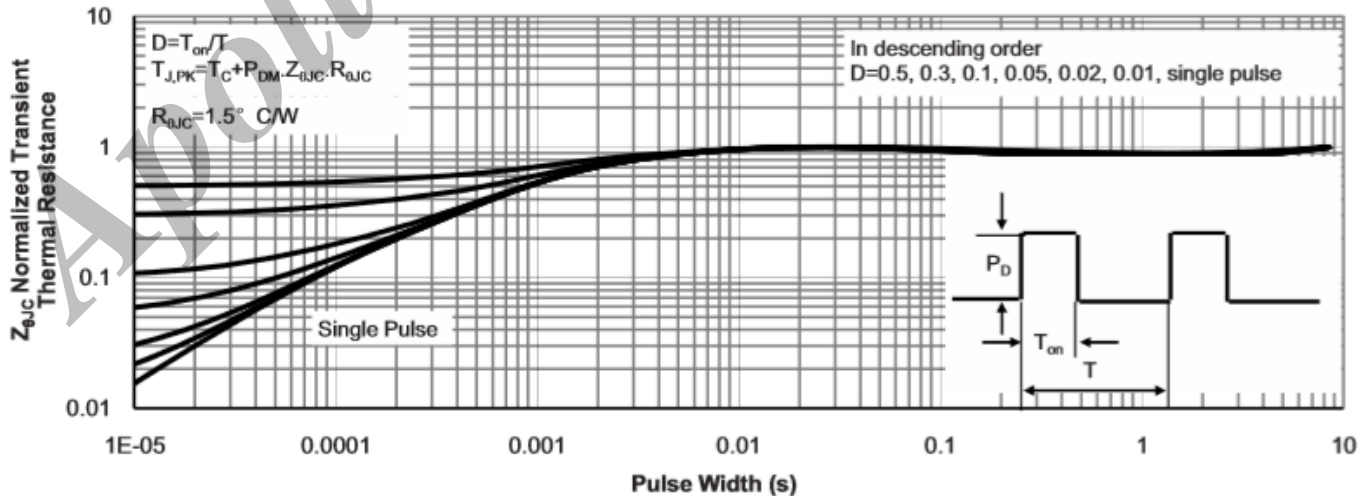


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

• Typical Characteristics

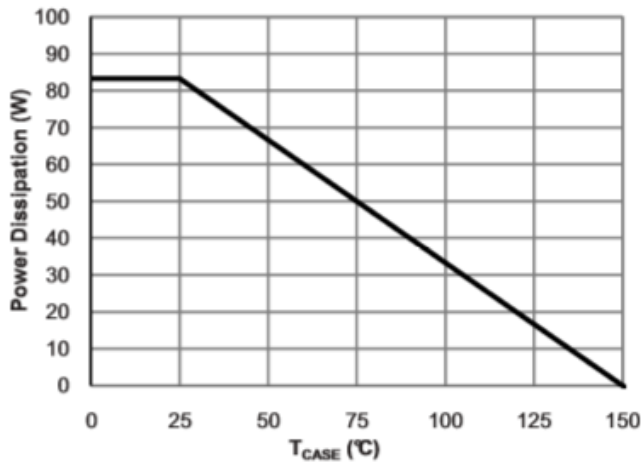


Figure 12: Power De-rating (Note F)

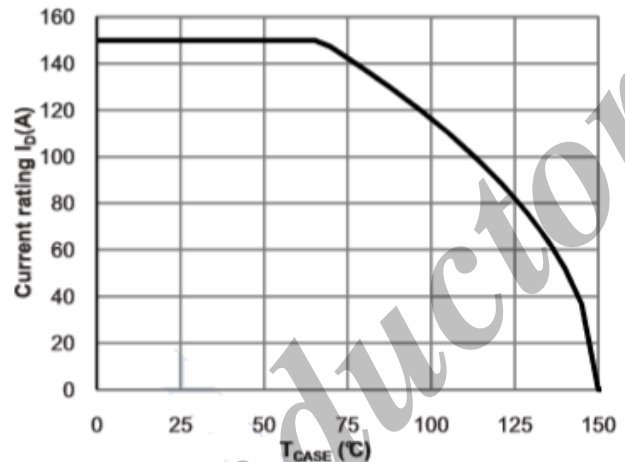


Figure 13: Current De-rating (Note F)

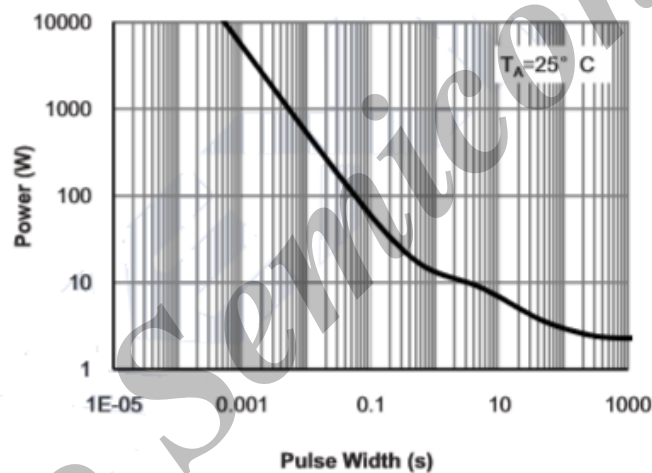


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

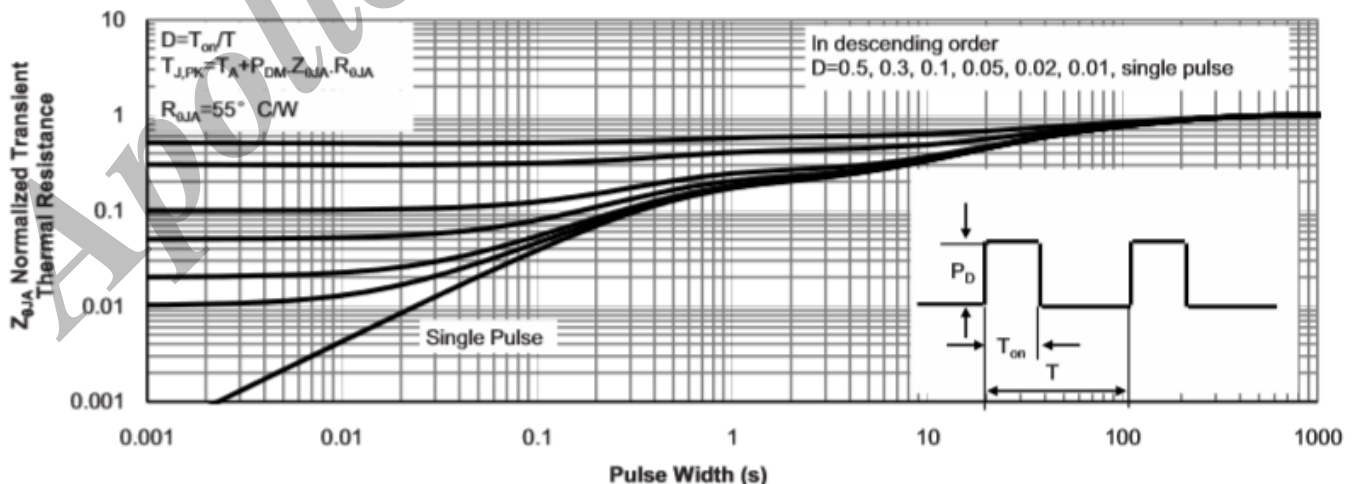
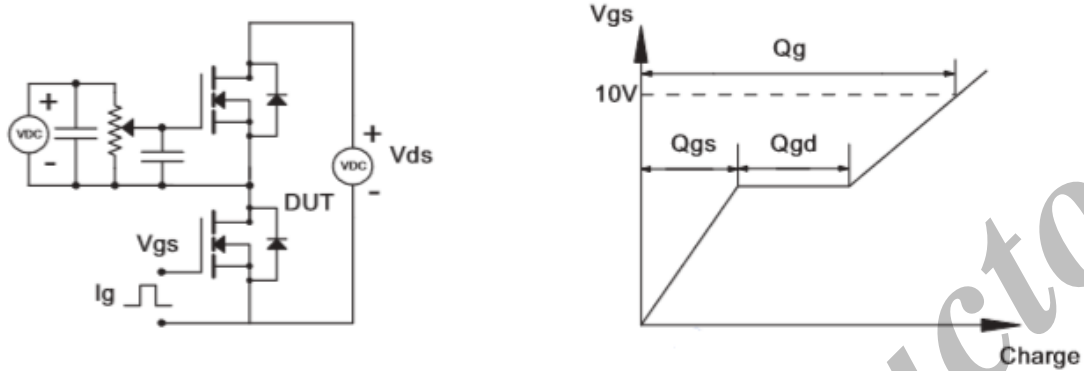
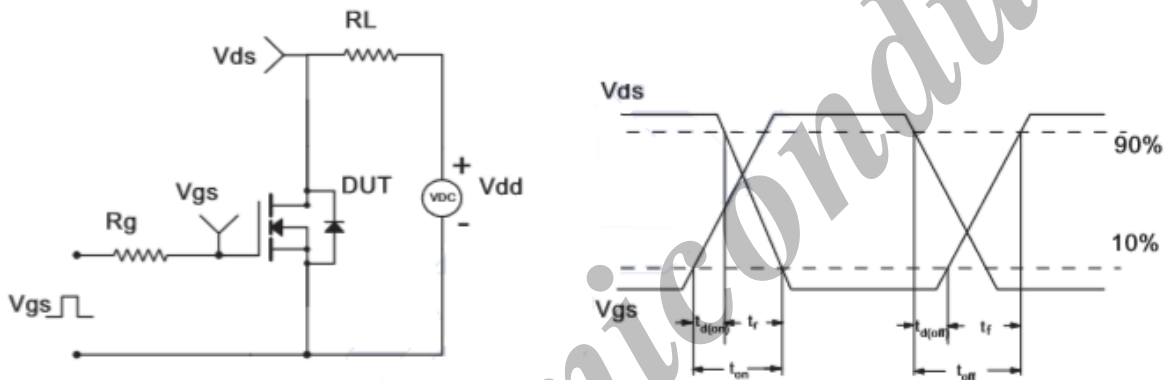


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

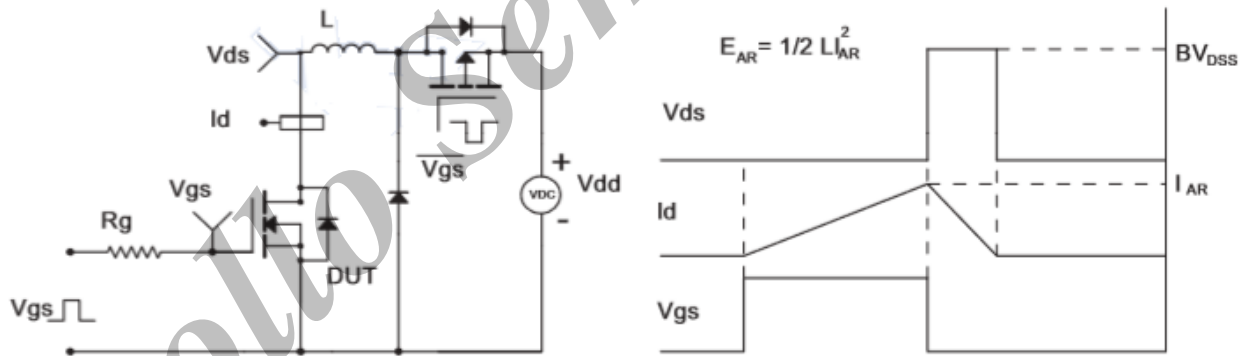
Gate Charge Test Circuit & Waveform



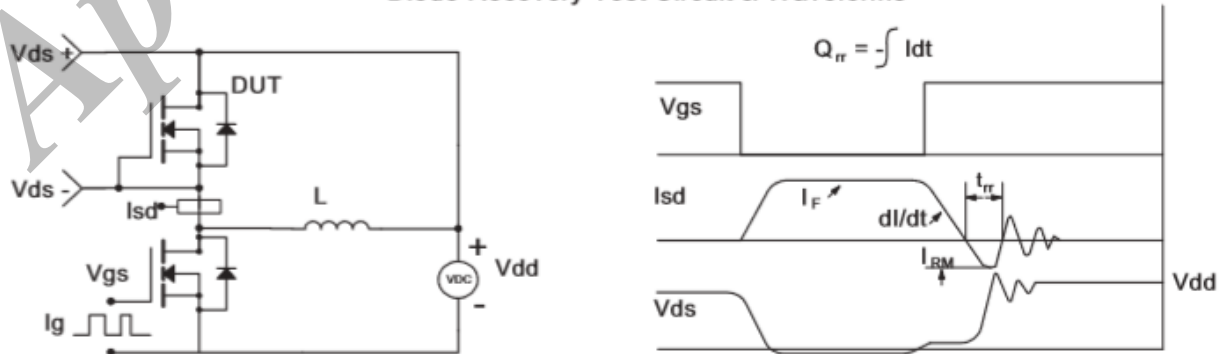
Resistive Switching Test Circuit & Waveforms



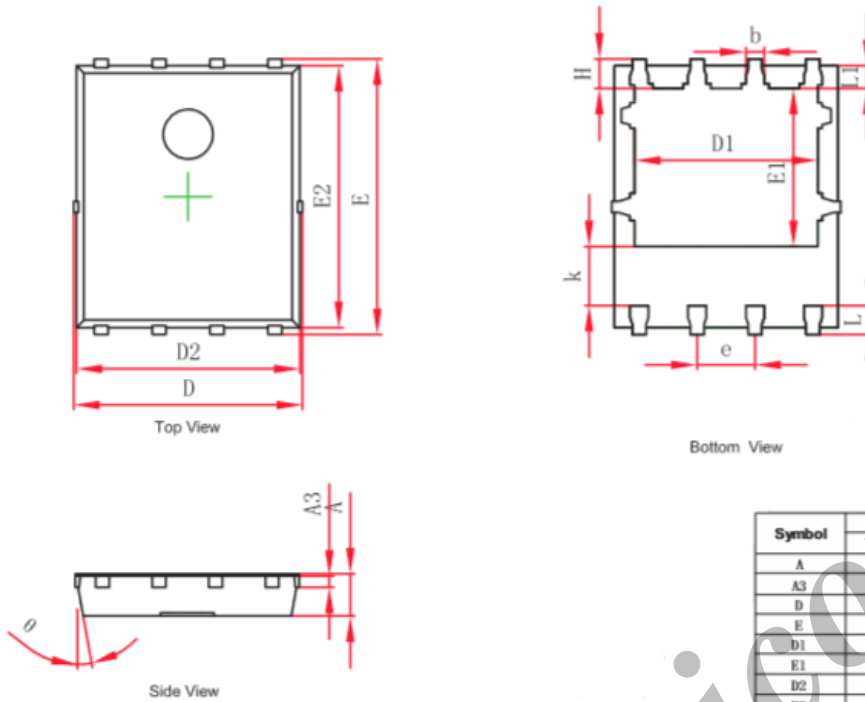
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

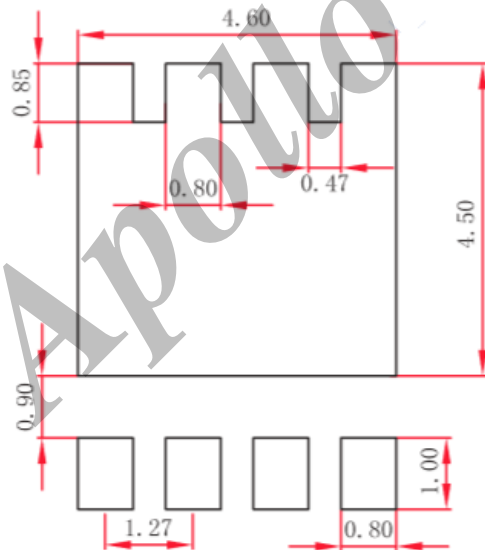


• **DFN5x6-8(PDFNWB5x6-8L) Package Outline Dimensions**



Symbol	Dimensions in Millimeters		Dimensions in Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254REF.		0.010REF.	
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.300	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP.		0.050TYP.	
l	0.559	0.711	0.022	0.028
l1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
theta	10°	12°	10°	12°

■ **DFN5x6-8(PDFNWB5x6-8L) Suggested Pad Layout**



Note:
 1. Controlling dimension: in millimeters.
 2. General tolerance: $\pm 0.05\text{mm}$.
 3. The pad layout is for reference purposes only.

Disclaimer

ALL PRODUCT, PRODUCT SPECIFICATIONS AND DATA ARE SUBJECT TO CHANGE WITHOUT NOTICE TO IMPROVE RELIABILITY, FUNCTION OR DESIGN OR OTHERWISE.

Apollo Semiconductor Ltd., its affiliates, agents, and employees, and all persons acting on its or their behalf (collectively, "Apollo"), disclaim any and all liability for any errors, inaccuracies or incompleteness contained in any datasheet or in any other disclosure relating to any product.

Apollo makes no warranty, representation or guarantee regarding the suitability of the products for any particular purpose or the continuing production of any product. To the maximum extent permitted by applicable law, Apollo disclaims (i) any and all liability arising out of the application or use of any product, (ii) any and all liability, including without limitation special, consequential or incidental damages, and (iii) any and all implied warranties, including warranties of fitness for particular purpose, non-infringement and merchantability.

Statements regarding the suitability of products for certain types of applications are based on Apollo's knowledge of typical requirements that are often placed on Apollo products in generic applications. Such statements are not binding statements about the suitability of products for a particular application. It is the customer's responsibility to validate that a particular product with the properties described in the product specification is suitable for use in a particular application. Parameters provided in datasheets and / or specifications may vary in different applications and performance may vary over time. All operating parameters, including typical parameters, must be validated for each customer application by the customer's technical experts. Product specifications do not expand or otherwise modify Apollo's terms and conditions of purchase, including but not limited to the warranty expressed therein.

Except as expressly indicated in writing, Apollo products are not designed for use in medical, life-saving, or life-sustaining applications or for any other application in which the failure of the Apollo product could result in personal injury or death. Customers using or selling Apollo products not expressly indicated for use in such applications do so at their own risk. Please contact authorized Apollo personnel to obtain written terms and conditions regarding products designed for such applications.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted by this document or by any conduct of Apollo. Product names and markings noted herein may be trademarks of their respective owners